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1 Hypergraph coloring and reconfigured RAM testing

Franklin, M.; Saluja, K.K.;
Computers, IEEE Transactions on , Volume: 43 , Issue: 6 , June 1994
Pages: 725 - 736

[Abstract] [PDF Full-Text (1184 KB)] **IEEE JNL**

2 Testing reconfigured RAM's and scrambled address RAM's for pattern sensitive faults

Franklin, M.; Saluja, K.K.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on , Volume: 15 , Issue: 9 , Sept. 1996
Pages: 1081 - 1087

[Abstract] [PDF Full-Text (708 KB)] **IEEE JNL**

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